Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSIV)

# 2SK3564

#### **Switching Regulator Applications**

• Low drain-source ON resistance: RDS (ON) =  $3.7 \Omega$  (typ.)

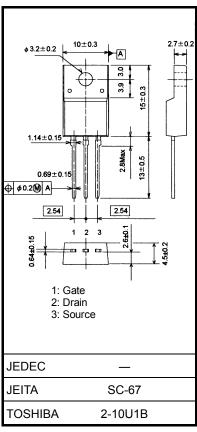
• High forward transfer admittance:  $|Y_{fs}| = 2.6 \text{ S (typ.)}$ 

• Low leakage current: IDSS = 100  $\,\mu$  A (VDS = 720 V)

• Enhancement mode:  $V_{th} = 2.0 \sim 4.0 \text{ V (VDS} = 10 \text{ V, ID} = 1 \text{ mA})$ 

### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	900	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	900	V	
Gate-source voltage		$V_{GSS}$	±30	V	
Drain current	DC (Note 1)	I <sub>D</sub>	3		
	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	9	Α	
Drain power dissipati	on (Tc = 25°C)	PD	40	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	408	mJ	
Avalanche current		I <sub>AR</sub>	3	Α	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	4.0	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 1.7 g (typ.)

www.DataS Note. Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

#### **Thermal Characteristics**

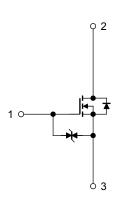
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	3.125	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$ , L = 83 mH,  $I_{AR} = 3.0 \text{ A}$ ,  $R_G = 25 \Omega$ 

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.





# **Electrical Characteristics (Ta = 25°C)**

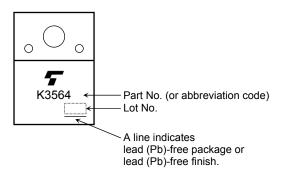
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Gate-source brea	akdown voltage	V (BR) GSS	$I_G = \pm 10 \mu A, V_{DS} = 0 V$	±30	_	_	V
Drain cut-off curre	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 720 V, V <sub>GS</sub> = 0 V		_	100	μА
Drain-source brea	akdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	900	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R <sub>DS (ON)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1.5 A	_	3.7	4.3	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 1.5 A	0.65	2.6	_	S
Input capacitance	9	C <sub>iss</sub>		_	700	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	15	_	pF
Output capacitance		C <sub>oss</sub>		_	75	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $V_{DD} \simeq 200 \text{ V}$	_	20	_	
	Turn-on time	t <sub>on</sub>		_	60	_	
	Fall time	t <sub>f</sub>		_	35	_	- ns
	Turn-off time	t <sub>off</sub>	Duty ≦ 1%, t <sub>W</sub> = 10 μs	_	125	_	
Total gate charge		Qg		_	17	_	
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}$	_	10	_	nC
Gate-drain charge		Q <sub>gd</sub>		_	7	_	

## **Source-Drain Ratings and Characteristics (Ta = 25°C)**

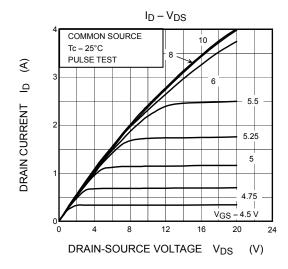
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_		_	3	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	9	Α
Forward voltage (diode)	V <sub>DSF</sub>	$I_{DR} = 3 A$ , $V_{GS} = 0 V$	_	_	-1.9	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = 3 \text{ A}, V_{GS} = 0 \text{ V},$	_	850	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dl <sub>DR</sub> /dt = 100 A/μs	_	4.7	_	μС

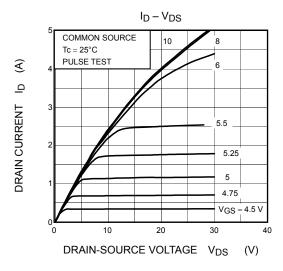
# Marking

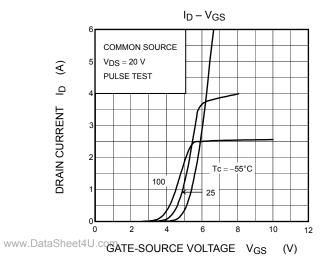
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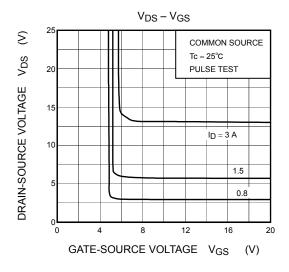


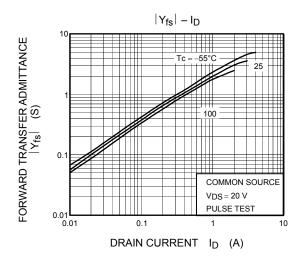
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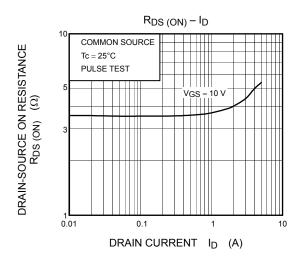




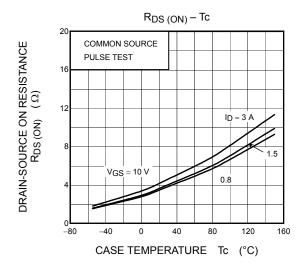


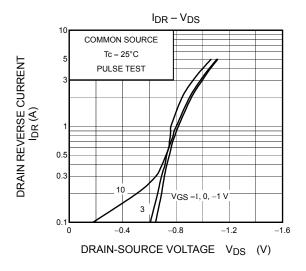


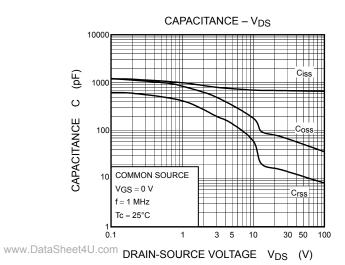


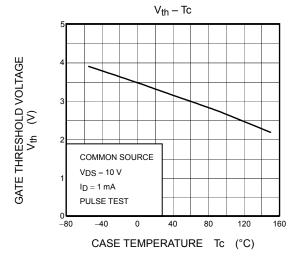


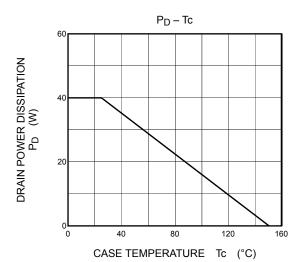
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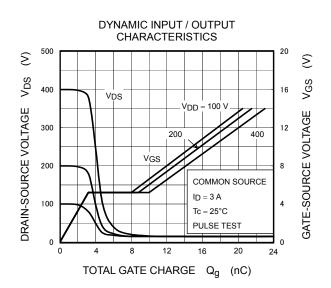


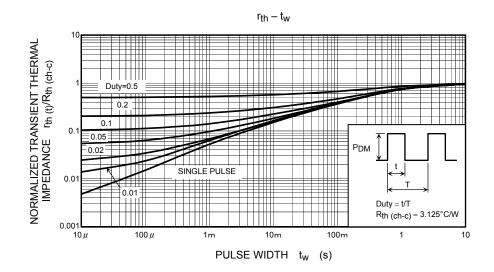


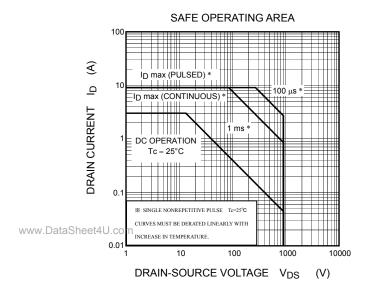


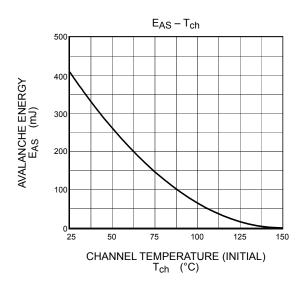


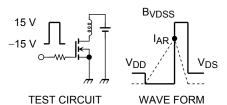












$$R_G = 25 \Omega$$
  
 $V_{DD} = 90 \text{ V, L} = 83\text{mH}$   $EAS = \frac{1}{2} \cdot \text{L} \cdot \text{I}^2 \cdot \left(\frac{\text{BVDSS}}{\text{BVDSS} - \text{VDD}}\right)$ 

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